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In the United States Patent and Trademark Office

Applicants: H. Rose et al

Group Art Unit: 2881

Patent Application
Serial No: 10/644,037

Examiner: Kalimah Fernandez

Filed: August 20, 2003

Attorney Docket: 01016

For: Particle Beam System
Having a Mirror Corrector

Information Disclosure Statement under 37 CFR 1.97(d)

Commissioner for Patents and Trademarks
P.O. Box 1450
Alexandria, Virginia 22313-1450

Dear Sir:

In connection with the filing of a further patent application based also on International patent application PCT/EP 02/01553, the enclosed information was made available to the applicants. Copies of the two articles cited and an English translation of German patent publication DE 39 31 970 A1 are submitted herewith.

A check in the amount of \$180.00 as set forth in 37 CFR 1.17(p) is submitted herewith. The Commissioner is authorized to charge any deficiency of payment to Deposit Account No. 15-0773.

08/20/2004 AADDFD1 00000058 10644037

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180.00 OP

Respectfully submitted,


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Date: August 19, 2004

Sheet 1 of 1Information Disclosure
Statement by applicantApplicants: H. Rose et al
Atty. Docket No: 01016
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U. S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Sub- Class	Filing Date if approp.
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FOREIGN PATENT DOCUMENTS

Document Number	Date	Country	Class	Sub- Class	Trans- lation yes	no
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39 31 970	04/1991	DE				
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

"Corrected Low-Energy Electron Microscope for Multi-Mode Operation", D. Preikszas
et al, Institute of Applied Physics, Darmstadt, Germany, pp. 197-198.

"A beam separator with small aberrations", H. Müller et al, Journal of Electron
Microscopy 48(3): 191-204 (1999).

Examiner: _____

Date Considered: _____